



Docket No.: M4065.0392/P392  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:  
Paul A. Farrar et al.

Allowed: August 12, 2004

Application No.: 09/773,522

Confirmation No.: 6270

Filed: February 2, 2001

Art Unit: 1762

For: MICRO C-4 SEMICONDUCTOR DIE  
AND METHOD FOR DEPOSITING  
CONNECTION SITES THEREON

Examiner: B. K. Talbot

**COMMENTS ON EXAMINER'S STATEMENT OF REASONS  
FOR ALLOWANCE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Applicant agrees in part with the Examiner's statement for allowance in that the prior art of record fails to disclose the invention as claimed. However, the Examiner's statement does not accurately reflect all of the language of each of the allowed claims. The totality of the language of each claim provides additional reasons for the allowance of each claim.

Dated: November 12, 2004

Respectfully submitted,

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